<u>EE 140</u>: Analog Integrated Circuits Lecture 4w: Inspection Analysis

Lecture 4: Inspection Analysis Announcements: Course website has been up and running http://www-inst.eecs.berkeley.edu/~ee140/sp11/ I'm here today, but as your syllabus shows, will be traveling again next Tuesday, 2/1 ♦ Flying back next Tuesday, 2/1 ♦ Make-up lecture: Lecture Topics: \$\rightarrow Procedure for Small Signal Analysis \$1-Tx Amplifier Examples Procedur in Small-Signal Analysis. Ex. Dirorele Common-Emitter Clef

Procedure:

- 1) Find the DC operating pt. got the DC rultager & Cumonts at all noder & branches, respectively
- 3 Defenire le small-signe (S.S.) parameter fa devices in the signel park.
- 3 Convert the full clot to the S.S. clot. = Zero out the DC source, - short out large caps.
- (4a) IF realed, replace the Xristan we its S.S. Clot.

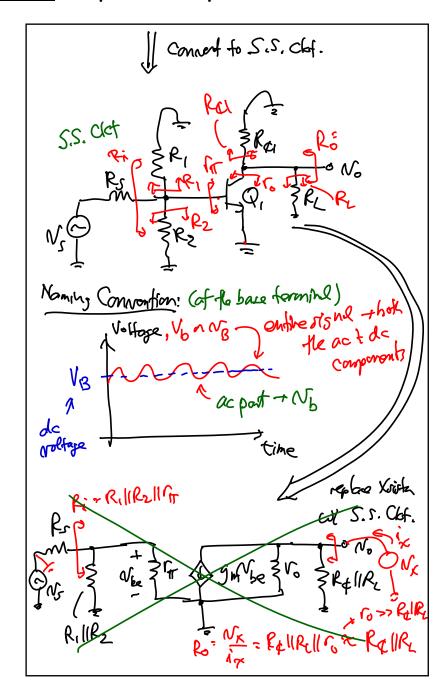
 It his should not be NOFDED often!

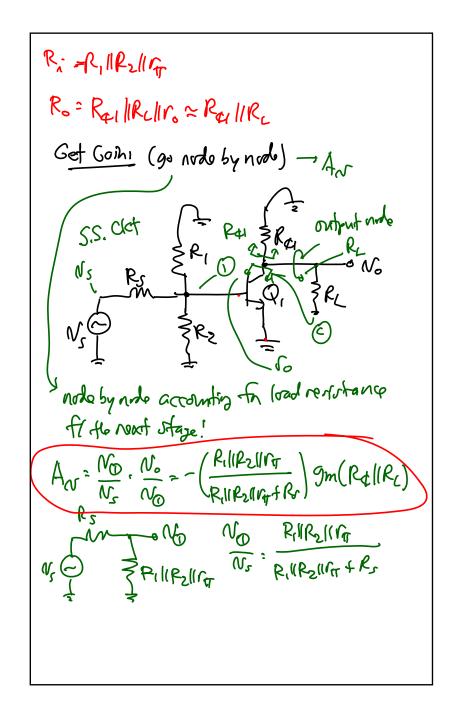
 When is it realed? generally, only is

 Cases when those is feedbooks
- 4b) Analyze by inspection based on prior 5.5.

 analysis experience!
- Go through Inspection Analysis handout
 Best to commit the equations on this sheet to memory

<u>EE 140</u>: Analog Integrated Circuits <u>Lecture 4w</u>: Inspection Analysis





<u>EE 140</u>: Analog Integrated Circuits <u>Lecture 4w</u>: Inspection Analysis

